

ABSTRACT

5 A method and system for monitoring the feature-extractability of microarrays
by integrating control-feature blocks, or reference pattern blocks within a
microarray. The embedded control features comprise an array of pattern blocks, or
reference pattern, in which each pattern block is composed of a set of microarray
features arranged in a specific pattern of low-intensity and high-intensity features.
10 Positive control features are designed to generate high-intensity signals following
exposure of the microarray to a sample solution, and negative control features are
designed to generate no signal or a low-intensity signal. The pattern blocks may be
visually inspected to determine the feature extractability of a microarray prior to
undertaking full, automated feature extraction, or may select a feature-extraction
15 method based on an analysis of the reference pattern.